

1) The outcomes of an experiment are integers between 10 and 20, inclusive. Thus the sample space $S = \{10, 11, 12, \dots, 20\}$. The probability of any outcome is proportional to the inverse of that number and is equal to $1.301/(\text{number})$. For example, $P(\text{outcome} = 10) = 1.301/10 = 0.1301$, $P(\text{outcome} = 11) = 1.301/11 = 0.1183$, etc. Define the event $A = \{\text{outcome is } 11, 13, 17, \text{ or } 19\}$ and $B = \{\text{outcome is exactly divisible by } 6\}$.

1a) [1] Compute $P(A)$

1b) [2] Compute $P(A \cup B)$

1c) [2] Compute $P(A \cap B)$

1d) [2] Compute $P(A|B)$

$$1A) P(A) = P(11 \text{ or } 13 \text{ or } 17 \text{ or } 19)$$

$$= P(11) + P(13) + P(17) + P(19) - 0 \quad (\text{Mutually Exclusive})$$

$$= .1183 + .1001 + .07653 + .06847$$

$$= \underline{\underline{.3634}} \text{ ANS}$$

$$1B) P(B) = P(12 \text{ or } 18) = P(12) + P(18) - 0$$

$$= .1084 + .07228 = .1807$$

$$P(A \cup B) = P(A) + P(B) - P(A \cap B)$$

$$= \underline{\underline{.5441}} \text{ ANS}$$

$$P(A|B) = \frac{P(A \cap B)}{P(B)}$$

$$= \frac{0}{.1807}$$

$$= \underline{\underline{0}} \text{ ANS}$$

1c) $P(A \cap B) = 0$ since no elements are in both sets.

2) [3] A digital chip contains 100 transistors and 400 connections. The probability of a faulty transistor is 0.001, and the probability of a faulty connection is 0.0001. What is the probability that a chip taken at random is defective, assuming all defects are statistically independent? Note that the chip is considered to be defective if it has ≥ 1 fault of any kind.

Event $A \triangleq$ all transistors good $\Rightarrow P(A) = .999^{100} = .9048$

Event $B \triangleq$ all connections good $\Rightarrow P(B) = .9999^{400} = .9608$

$$P(\text{chip is good}) = P(A \cap B) = P(A)P(B) = .9048 (.9608) = .8693$$

$$P(\text{chip is bad}) = 1 - P(\text{chip is good}) = \underline{\underline{.1307}} \text{ ANS}$$

Note: $P(A) = P(\text{transistor } \#1 \text{ is good} \cap \text{transistor } \#2 \text{ is good} \cap \dots \cap \text{transistor } \#100 \text{ is good})$ S.I.
 $= P(\text{transistor } \#1 \text{ is good}) P(\text{transistor } \#2 \text{ is good}) \dots P(\text{transistor } \#100 \text{ is good}) = P(\text{good})^{100}$

2) Alternatively

Event A = ≥ 1 transistor bad

$$P(A) = 1 - P(\text{all good}) \\ = .0952$$

Event B = ≥ 1 connection bad

$$P(B) = 1 - P(\text{all good}) \\ = .0392$$

Event

$C \triangleq$ Chip is Bad

= A or B = A + B

$$\Rightarrow P(C) = P(A+B)$$

$$P(C) = P(A) + P(B) - P(AB)$$

$$= P(A) + P(B) - P(A)P(B)$$

S.I.

$$= .0952 + .0392 - (.0952)(.0392) = .1344 - .00373$$

$$= \underline{\underline{.1307}} \text{ ANS}$$